**************************************	<u> </u>	US Dept. of Commerc	of Commerce ATTY DOCKET NO. ARK OFFICE 117087			APPLICATION NO. 10/663,902		
REV. 8-83) PATENT & TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)			117007			10/00	3,902	
				APPLICANT Satoshi TANENAKA				
			FILING Septemb	DATE per 17, 2003				
		U.S.	PATENT DOC	UMENTS				
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		DOCUMENT NUMBER	DATE	(COUNTRY		CLASS	SU. CLA
80	1	JP A 7-142735 (with abstract and translation)	06/02/1995	Japan				
Ea	2	JP A 6-120249 (with abstract and translation)	04/28/1994	Japan				
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		· OTHER DOCUMENTS (In	cluding Author	Title, Date, Pertin	ent Pages, etc.)			
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Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

DATE CONSIDERED 8-15-04

Date: February 5, 2004

EXAMINER

Examiner:

Sheet	1	of	1	
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Form PTO-144 (REV. 8-83)	9	US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 117087 APPLICATION NO. New US Application					
INFORMATION DISCLOSURE STATEMENT								
(Use several sheets if necessary)			APPLICANT Satoshi TAKENAKA					
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